

## Annex 4: Test setup photographs 22-1-0076802T12a-A4

<b>Number of pages:</b>	6	<b>Date of Report:</b>	2022-Nov-07
<b>Testing company:</b>	CETECOM GmbH Im Teelbruch 116 45219 Essen Germany Tel. + 49 (0) 20 54 / 95 19-0 Fax: + 49 (0) 20 54 / 95 19-150	<b>Applicant:</b>	WITTE-Velbert GmbH & Co.KG
<b>Product:</b>	Automotive NFC Outer Door Handle		
<b>Model:</b>	INTTAGEBTP		
<b>FCC ID:</b>	V2T-INTTAGEBTP	<b>IC:</b>	7575A-INTTAGEBTP
<b>Testing has been carried out in accordance with:</b>	<b>FCC Regulations</b> Title 47 CFR, Chapter I, Subchapter A, Part 15, Subpart C §15.225	<b>ISED Regulations</b> RSS-Gen, Issue 5 + Amendment 2 RSS-210, Issue 10	Deviations, modifications or clarifications (if any) to above mentioned documents are written in each section under "Test method and limit".each section under "Test method and limit".

## Table of Contents

1	Test setup photographs.....	3
	Photograph 1 : Setup for extreme temperature measurement, close up view, without NFC-Tag .....	3
	Photograph 2 : Setup for extreme temperature measurement, close up view, with NFC-Tag .....	3
	Photograph 3 : Setup for extreme temperature measurement, overview.....	4
	Photograph 4 : Setup in the semi anechoic chamber, measurement <30 MHz, overview, without NFC-Tag .....	4
	Photograph 5 : Setup in the semi anechoic chamber, measurement <30 MHz, close up view, with NFC-Tag.....	5
	Photograph 6 : Setup in the semi anechoic chamber, measurement >30 MHz, overview, with NFC-Tag.....	5
	Photograph 7 : Setup in the semi anechoic chamber, measurement >30 MHz, close up view, with NFC-Tag.....	6

## 1 Test setup photographs



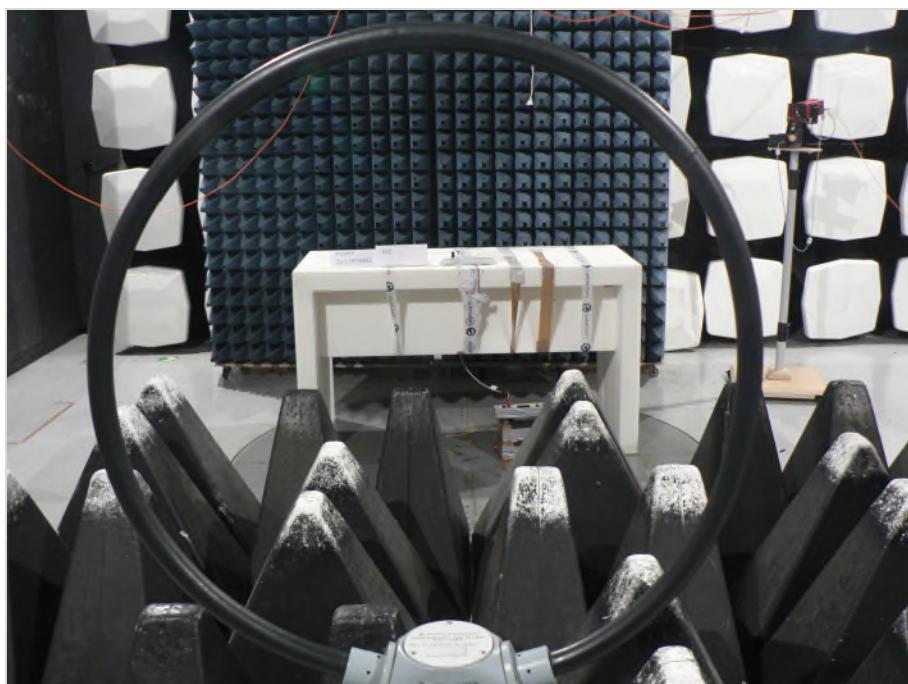
Photograph 1: Setup for extreme temperature measurement, close up view, without NFC-Tag



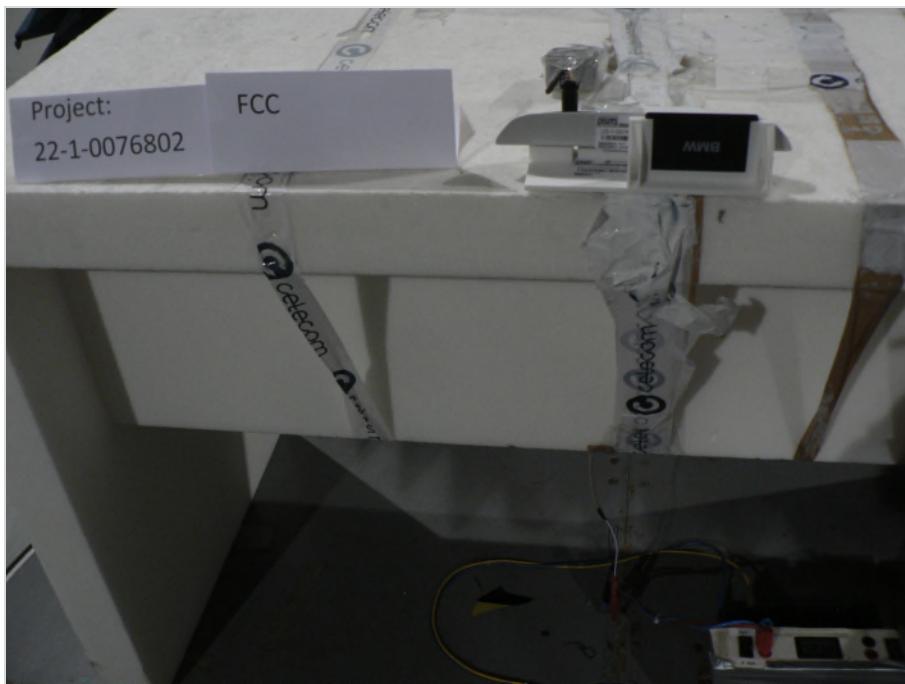
Photograph 2: Setup for extreme temperature measurement, close up view, with NFC-Tag



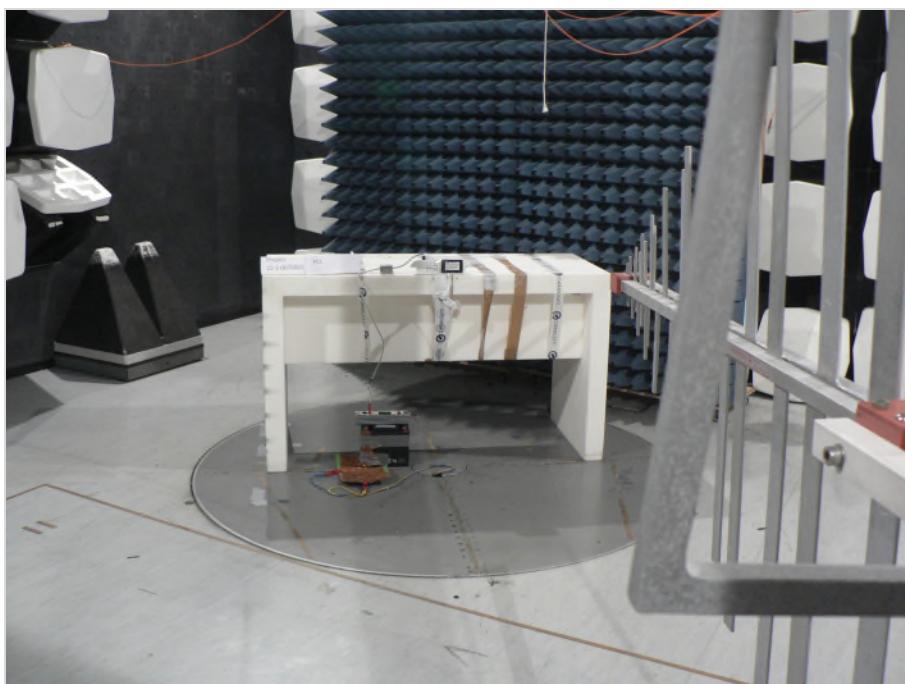
**Photograph 3:** Setup for extreme temperature measurement, overview



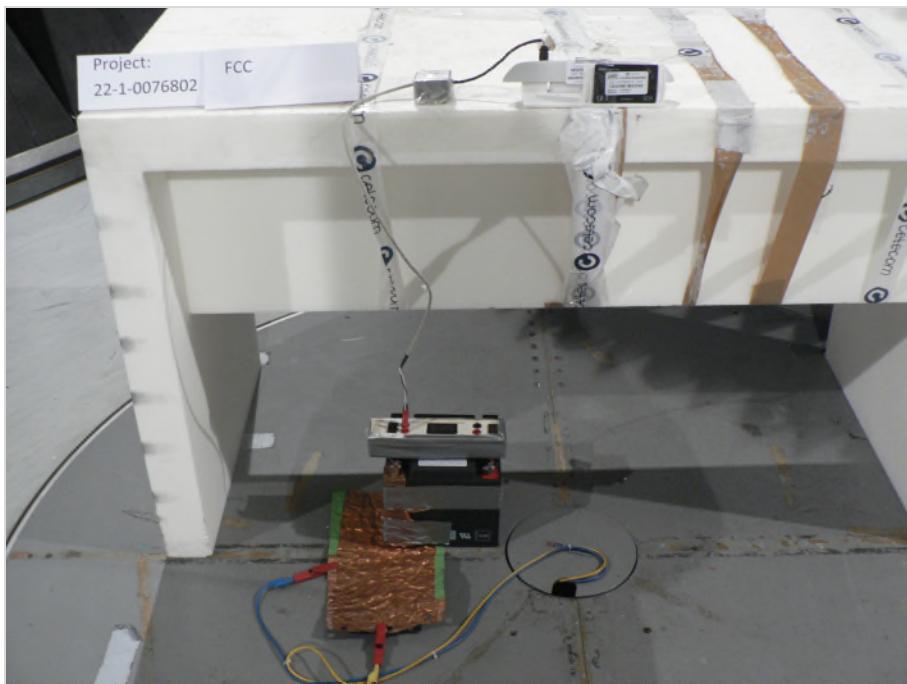
**Photograph 4:** Setup in the semi anechoic chamber, measurement <30 MHz, overview, without NFC-Tag



**Photograph 5:** Setup in the semi anechoic chamber, measurement <30 MHz, close up view, with NFC-Tag



**Photograph 6:** Setup in the semi anechoic chamber, measurement >30 MHz, overview, with NFC-Tag



**Photograph 7: Setup in the semi anechoic chamber, measurement >30 MHz, close up view, with NFC-Tag**

## End Of Annex 4